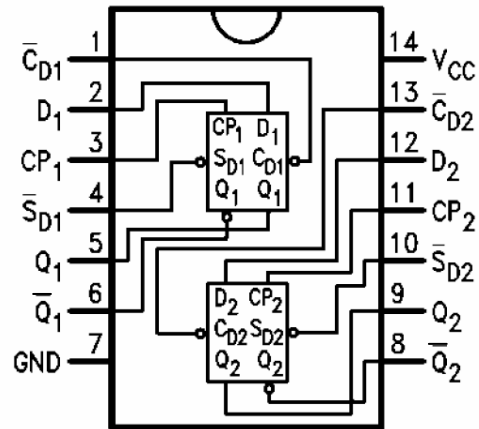
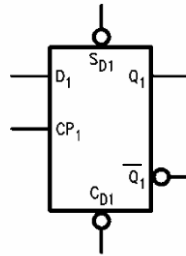


## Laboratory 3: Flip-Flops

1. Use two 74LS00 NAND gates to create an “SR latch”. Use slider switches as inputs. Verify its truth table. The standard notation for a  $Q$  output that does not change is  $Q_0$ . The “0” subscript implies that the current value is the same as the previous value. Now use a switch to “trigger” the latch as it falls from high to low (a *falling edge*). You should be able to see the switch output bouncing between the two states from the sliders if you slide one SLOWLY. Verify that putting switch through a latch “debounces” the switch.
2. Use two more 74LS00 NANDs and an inverter to create a clocked D-type latch. Verify its truth table.
3. Make another clocked SR latch from 74LS00 gates. Combine the two latches to make a master/slave edge-triggered flip-flop. Verify its truth table. Measure the propagation delay between the clock edge and when the data appears on  $Q$ . Measure the rise and fall times of the transitions on the output. Estimate the gate delay of a single TTL NAND. What do you think will be the maximum clock frequency that your device can handle? Explain.
4. Use a 74LS74 D-type edge-triggered flip-flop, construct a truth table, and compare its performance to your previous devices (e.g. the propagation delay). Note that this chip also has  $S$  and  $R$  inputs so you can set the state to a specific value. Also note the negative true nature of these inputs.

## D-Type Edge-Triggered Flip-Flop

Inputs				Outputs	
$\bar{S}_D$	$\bar{C}_D$	CP	D	Q	$\bar{Q}$
L	H	X	X	H	L
H	L	X	X	L	H
L	L	X	X	H	H
H	H	—	H	H	L
H	H	—	L	L	H
H	H	L	X	$Q_0$	$\bar{Q}_0$



Pin Names	Description
$D_1, D_2$	Data Inputs
$CP_1, CP_2$	Clock Pulse Inputs
$\bar{C}_D1, \bar{C}_D2$	Direct Clear Inputs
$\bar{S}_D1, \bar{S}_D2$	Direct Set Inputs
$Q_1, \bar{Q}_1, Q_2, \bar{Q}_2$	Outputs